

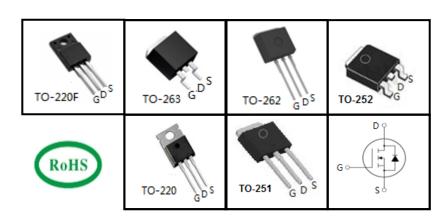
800V Super-Junction Power MOSFET

FEATURES

- $\bullet \quad \text{Very low FOM R}_{\text{DS(on)}} \times \text{Q}_{\text{g}} \\$
- 100% avalanche tested
- RoHS compliant

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)



Device Marking and Package Information						
Device	TPA80R2K2C	TPB80R2K2C	TPC80R2K2C	TPD80R2K2C	TPP80R2K2C	TPU80R2K2C
Package	TO-220F	TO-263	TO-262	TO-252	TO-220	TO-251
Marking	80R2K2C	80R2K2C	80R2K2C	80R2K2C	80R2K2C	80R2K2C

Absolute Maximum Ratings $T_C = 25^{\circ}C$, unless otherwise noted					
_			Value		Unit
Parameter	Symbol		TO-220, TO-251, TO-252 TO-262, TO-263		
Drain-Source Voltage (V _{GS} = 0V)		V_{DSS}	800		V
Continuous Drain Current		I _D	2		Α
Pulsed Drain Current	(note1)	I _{DM}	6		Α
Gate-Source Voltage		V_{GSS}	±30		V
Single Pulse Avalanche Energy	(note2)	E _{AS}	52.8		mJ
Avalanche Current	(note1)	I _{AR}	0.8		Α
Repetitive Avalanche Energy	(note1)	E _{AR}	0.09		mJ
MOSFET dv/dt Ruggedness(V _{DS} = 0 480V)		dv/dt	50		V/ns
Power Dissipation (T _C = 25°C)		P _D 28 23		W	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55~+150		°C

Thermal Resistance					
		Value			
Parameter	Symbol	TO-220, TO-251, TO-252 TO-262, TO-263	TO-220F	Unit	
Thermal Resistance, Junction-to-Case	R _{thJC}	4.4	5.5	°C/W	
Thermal Resistance, Junction-to-Ambient	R _{thJA}	62	80	30/00	

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${\tt TPA80R2K2C,\,TPB80R2K2C,\,TPC80R2K2C,\,TPD80R2K2C,\,TPP80R2K2C,\,TPU80R2K2C}$

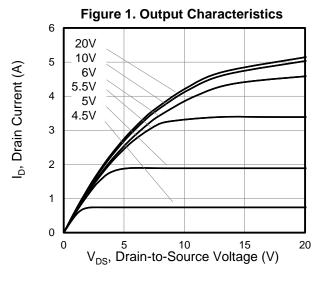
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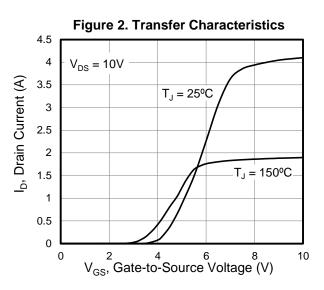
Specifications $T_J = 25^{\circ}C$, ur	Symbol Test Conditions			Value		
Parameter			Min. Typ. Max.		Unit	
Static				<u> </u>		
Drain-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0V, I_D = 250\mu A$	800			V
Zero Gate Voltage Drain Current		$V_{DS} = 800V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	
	I _{DSS}	V _{DS} = 800V, V _{GS} = 0V, T _J = 150°C			100	μA
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 30V$			±100	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.5	V
Drain-Source On-Resistance (Note3)	R _{DS(on)}	V _{GS} = 10V, I _D = 1A		1.8	2.2	Ω
Forward Transconductance (Note3)	g _{fs}	V _{DS} = 10V, I _D = 1A		3		S
Dynamic		· · ·		•	-	
Input Capacitance	C _{iss}	V 0V		390		
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = 50V,$		34		pF
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		5.3		
Total Gate Charge	Q_g			12		
Gate-Source Charge	Q_{gs}	$V_{DD} = 640V, I_{D} = 2A, V_{GS} = 10V$		2.5		nC
Gate-Drain Charge	Q_{gd}			5		
Turn-on Delay Time	t _{d(on)}			36		
Turn-on Rise Time	t _r	$V_{DD} = 400V, I_{D} = 2A,$		27		
Turn-off Delay Time	t _{d(off)}	$R_{G} = 25\Omega$		79		ns
Turn-off Fall Time	t _f			29		
Drain-Source Body Diode Characteris	stics				•	
Continuous Body Diode Current	Is	T 0500			2	Λ
Pulsed Diode Forward Current	I _{SM}	T _C = 25°C			6	А
Reverse Diode dv/dt	dv/dt	V _{DS} = 0 400V, I _{SD} ≤ I _D			15	V/ns
Body Diode Voltage	V _{SD}	$T_J = 25^{\circ}\text{C}, I_{SD} = 2\text{A}, V_{GS} = 0\text{V}$		0.9	1.2	V
Reverse Recovery Time	t _{rr}			220		ns
Reverse Recovery Charge	Q _{rr}	$V_R = 400V, I_F = I_S,$ $d_{I_F}/dt = 100A/\mu s$		0.9		μC
Peak Reverse Recovery Current	I _{rrm}	1		8		А

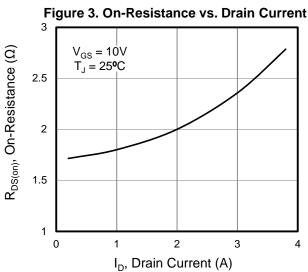
Notes

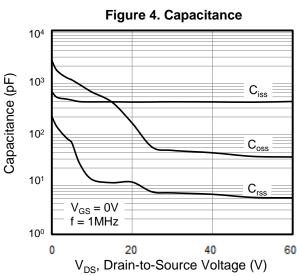
- 1. Repetitive Rating: Pulse Width limited by maximum junction temperature
- 2. $I_{AS} = 0.8A$, $V_{DD} = 50V$, $R_G = 25\Omega$, Starting $T_J = 25^{\circ}C$
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 1%

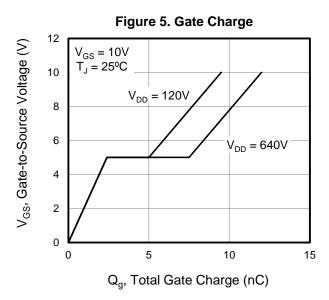
Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted

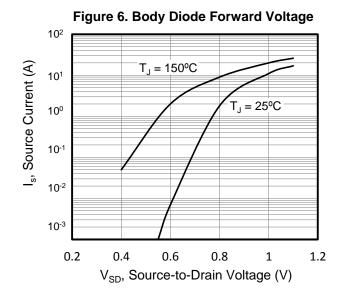










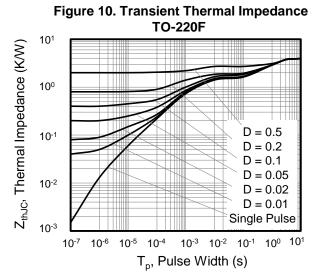


Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

Figure 7. On-Resistance vs. **Junction Temperature** 3 $V_{GS} = 10V$ R_{DS(on)}, (Normalized) 2.5 $I_D = 1A$ 1.5 0.5 0 0 -100 -50 50 100 150 200 T_J, Junction Temperature (°C)

Figure 8. Threshold Voltage vs. **Junction Temperature** 0.6 $I_{D} = 250 \mu A$ 0.4 V_{GS(th)}, (Variance)we 0.2 0 -0.2 -0.4 -0.6 -0.8 -1 -1.2 -100 -50 100 150 200 T_J, Junction Temperature (°C)

Figure 9. Transient Thermal Impedance TO-220,TO-251,TO-252,TO-262,TO-263 10¹ Z_{thJC}, Thermal Impedance (K/W) 10⁰ 10-1 D = 0.5D = 0.2D = 0.1D = 0.0510-2 D = 0.02D = 0.01Single Pulse 10-3 10-6 10-4 10-2 10-1 T_p, Pulse Width (s)



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Figure A: Gate Charge Test Circuit and Waveform

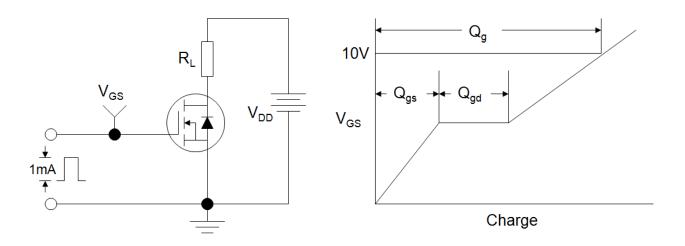


Figure B: Resistive Switching Test Circuit and Waveform

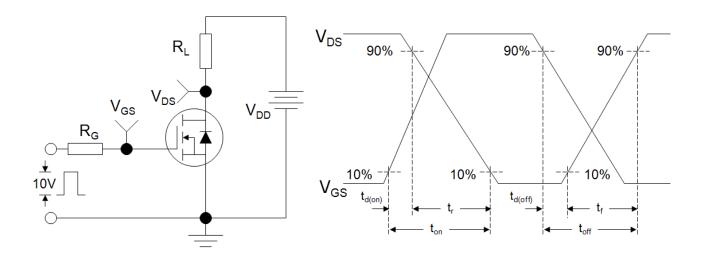
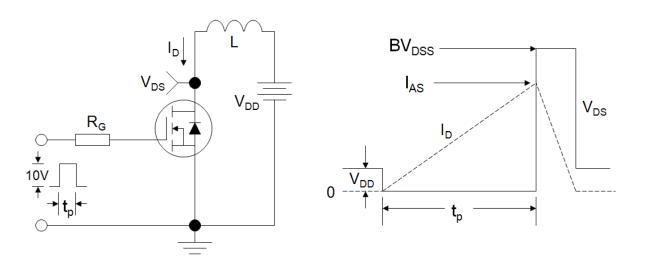
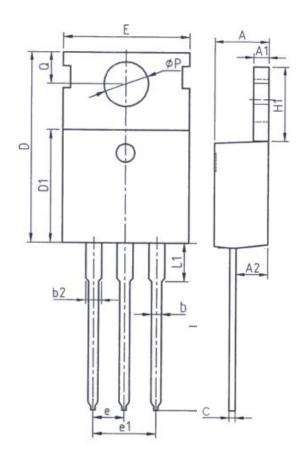


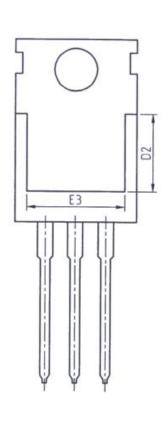
Figure C: Unclamped Inductive Switching Test Circuit and Waveform



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TO-220

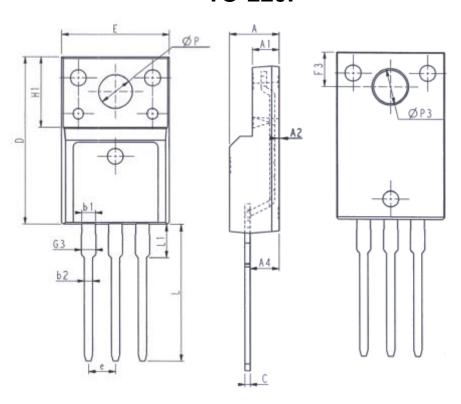




Unit: mm					
Symbol	Min.	Max.			
Α	4. 37	4. 77			
A1	1. 25	1. 45			
A2	2. 20	2. 60			
ь	0. 70	0. 95			
b2	1. 17	1. 47			
С	0. 40	0. 65			
D	15. 10	16. 10			
D1	8. 80	9. 40			
D2	5. 50	_			

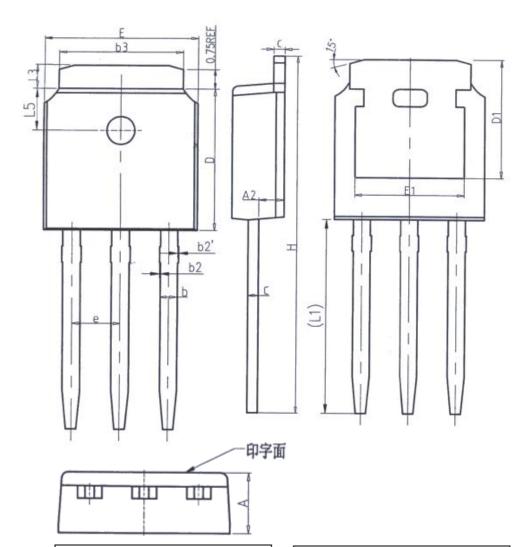
Unit: mm				
Symbol	Min.	Max.		
E	9. 70	10.30		
E3	7. 00	ı		
е	2. 54BSC			
e1	5. 08BSC			
H1	6. 25	6. 85		
L	12. 75	13.80		
L1	-	3. 40		
P	3. 40	3. 80		
Q	2. 60	3.00		

TO-220F



Unit: mm			Unit: mm		
Symbol	Min.	Max.	Symbol	Min.	Max.
E	9. 96	10.36	L	12. 68	13. 28
Α	4. 50	4. 90	L1	2. 93	3. 13
A1	2. 34	2. 74	Р	3. 03	3. 38
A2	0. 30	0.60	P3	3. 15	3. 65
A4	2. 56	2. 96	F3	3. 15	3. 45
С	0.40	0. 65	G3	1. 25	1. 55
D	15. 57	16. 17	b1	1. 18	1. 43
H1	6. 70	REF	b2	0. 70	0. 95
e	2.54	4BSC			

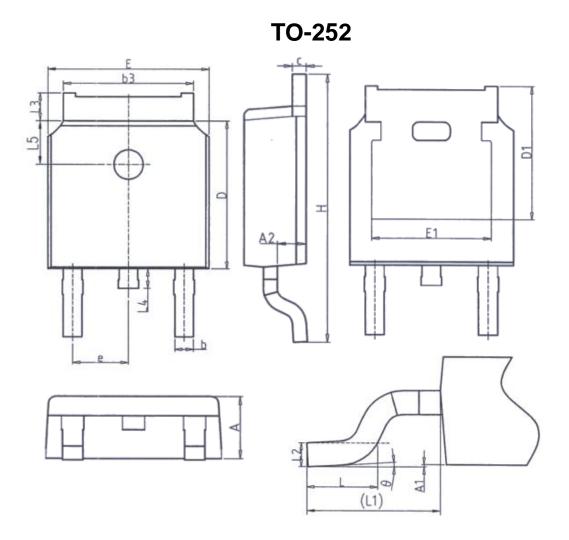
TO-251



Unit: mm					
Symbol	Min.	Max.			
Α	2. 20	2. 40			
A2	0. 97	1. 17			
b	0. 68	0. 90			
b2	0.00	0.10			
b2′	0.00	0.10			
b3	5. 20	5. 50			
С	0. 43	0. 63			
D	5. 98	6. 22			

Unit: mm				
Symbol	Min.	Max.		
D1	5. 30REF			
E	6. 40	6. 80		
E1	4. 63	-		
е	2. 286BSC			
Н	16. 22	16. 82		
L1	9. 15	9. 65		
L3	0.88	1. 28		
L5	1. 65	1. 95		

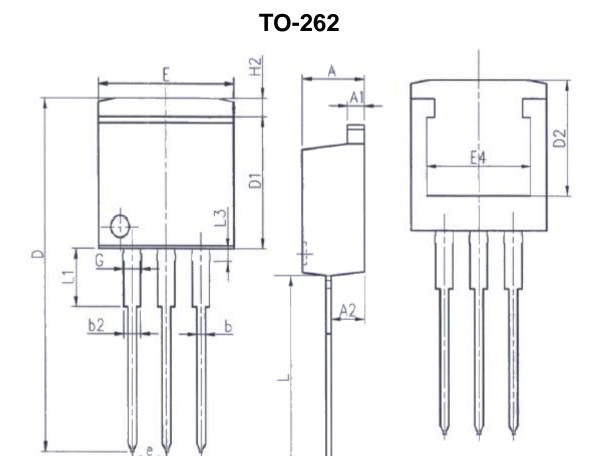




Unit: mm					
Symbol	Min.	Max.			
Α	2. 20	2. 40			
A1	0.00	0. 20			
A2	0. 97	1. 17			
b	0. 68	0. 90			
b3	5. 20	5. 50			
С	0. 43	0. 63			
D	5. 98	6. 22			
D1	5. 30REF				
E	6. 40	6. 80			
E1	4. 63	_			

Unit: mm				
Symbol	Min.	Max.		
е	2. 28	6BSC		
Н	9. 40	10.50		
L	1. 38	1. 75		
L1	2. 90REF			
L2	0. 51	IBSC		
L3	0.88	1. 28		
L4	- 1.00			
L5	1. 65	1. 95		
θ	0°	8°		

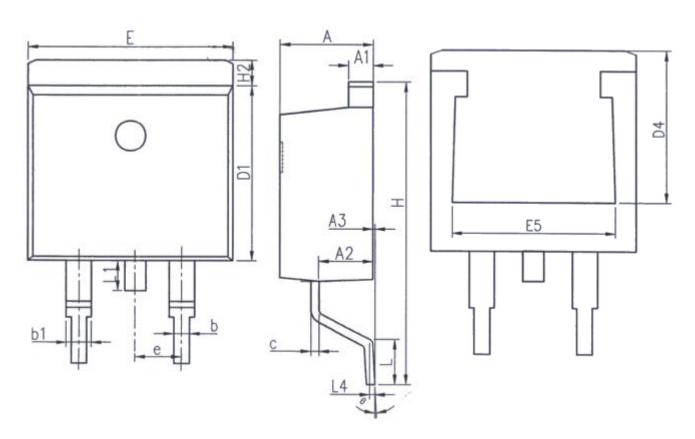




Unit: mm				
Symbol	Min.	Max.		
Α	4. 37	4. 77		
A1	1. 22	1. 42		
A2	2. 47	2. 87		
b	0. 70	0. 97		
b2	1. 17	1. 42		
С	0. 28	0.53		
D	23. 20	24. 02		
D1	8. 38	8. 90		
D2	6. 00	_		

Unit: mm			
Symbol	Min.	Max.	
E	9. 90	10. 39	
E4	7. 30	_	
e	2. 54BSC		
G	1. 25	1.50	
H2	-	1. 31	
L	13. 34	14. 10	
L1	3. 30	4. 06	
L3	0. 95	1. 15	

TO-263



Unit: mm		
Symbol	Min.	Max.
Α	4. 37	4. 77
A 1	1. 22	1. 42
A2	2. 49	2. 89
A3	0. 00	0. 25
b	0. 70	0. 96
b1	1. 17	1. 47
С	0. 30	0. 53
D1	8. 50	8. 90
D4	6. 60	_

Unit: mm			
Symbol	Min.	Max.	
E	9.86	10.36	
E 5	7. 06	-	
е	2. 54BSC		
Н	14. 70	15. 50	
H2	1. 07	1. 47	
L	2.00	2. 60	
L1	1. 40	1. 70	
L4	0. 25BSC		
θ	0°	9°	





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